



AGH UNIVERSITY OF SCIENCE AND TECHNOLOGY

#### **Progress in the LumiCal readout electronics**



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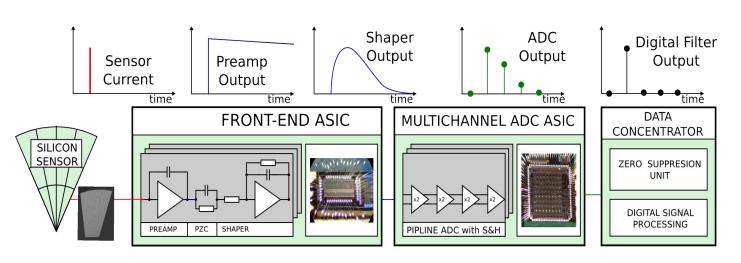


#### **Outline**

- Introduction and Where we are
- ASIC developments in CMOS 130 nm
- Analog front-end
- ADC conversion
- Summary and Plans



#### Introduction LumiCal detector readout chain





#### **Existing LumiCal detector readout comprises:**

- 8 channel front-end ASIC with preamp & CR-RC shaper Tpeak~60ns, ~9mW (AMS 0.35um)
- 8 channel pipeline ADC ASIC, Tsmp<=25MS/s, ~1.2mW/MHz (AMS 0.35um)
- FPGA based data concentrator and further readout

#### New developments for LumiCal detector readout:

- Prototype front-end ASIC in CMOS 130 nm under development... (main subject of this talk)
- Prototype SAR ADC ASIC in CMOS 130 nm fabricated and working well, already presented

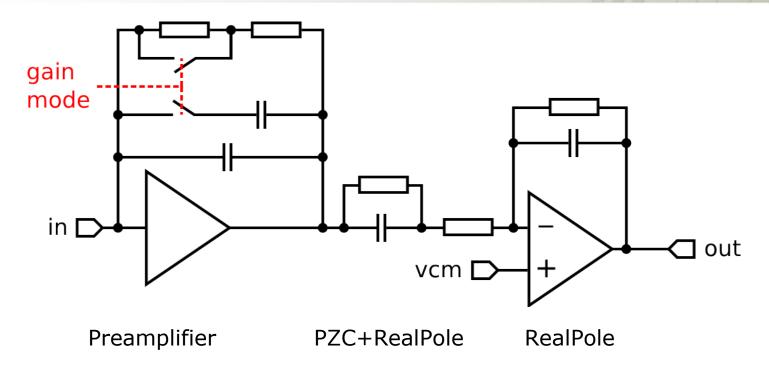


#### LumiCal front-end in CMOS 130 nm Specifications

- CMOS 130 nm technology
- 8 channels
- Detector capacitance  $C_{det} \approx 5 \div 50 pF$
- CR-RC shaping with peaking time  $T_{peak} \approx 50 \text{ ns}$
- Variable gain:
- calibration mode MIP sensitivity
- physics mode input charge up to ~6 pC
- Power pulsing
- Peak power consumption ~1.5 mW/channel
- Pitch ~140 um
- Noise: ENC ~ 1000e⁻ @10pF
- Crosstalk < 1%



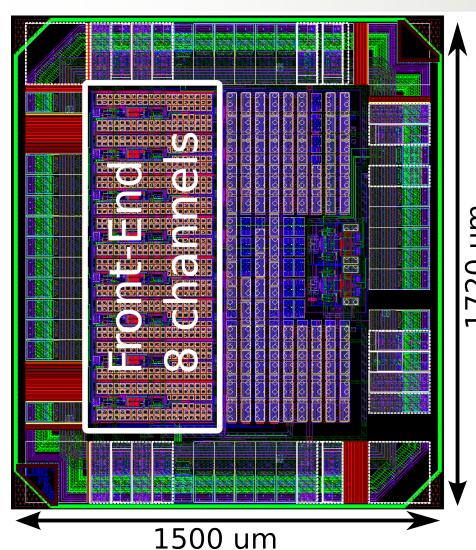
#### Analog Front-End Architecture



- Two gain modes (calibration and physics) applied by switching R,C components in preamplifier feedback circuit
- Simple CR-RC pulse shaping choosed to simplify the deconvolution procedure in further Digital Signal Processing (DSP)

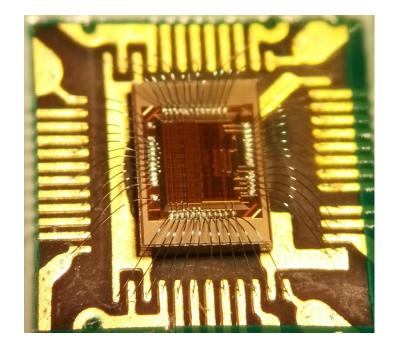


### **Analog Front-End Prototype ASIC**



Front-end ASIC prototype contains:

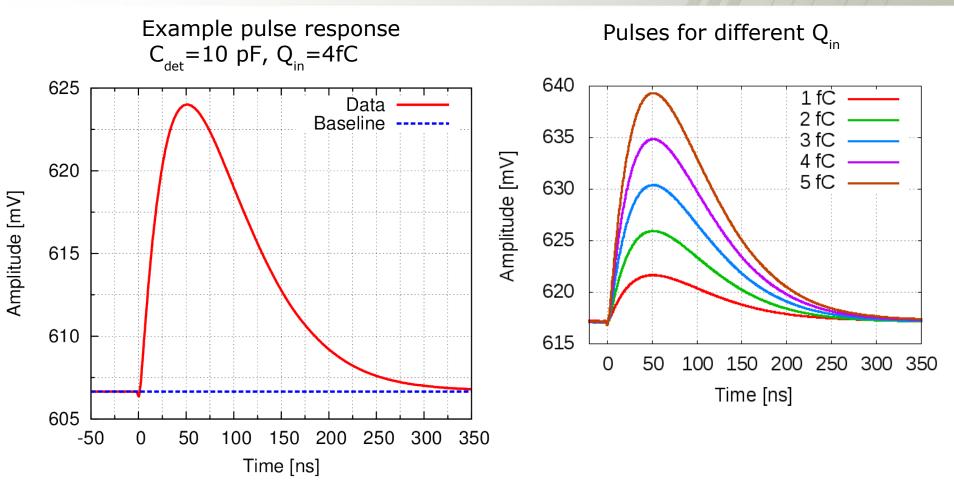
- 8 channels of Preamplifier&Shaper in pitch of 140 um
- 2 channels of Single-to-Differential converter



Design submitted in February 2013



## **Analog Front-End measurements Pulse response in high gain mode**



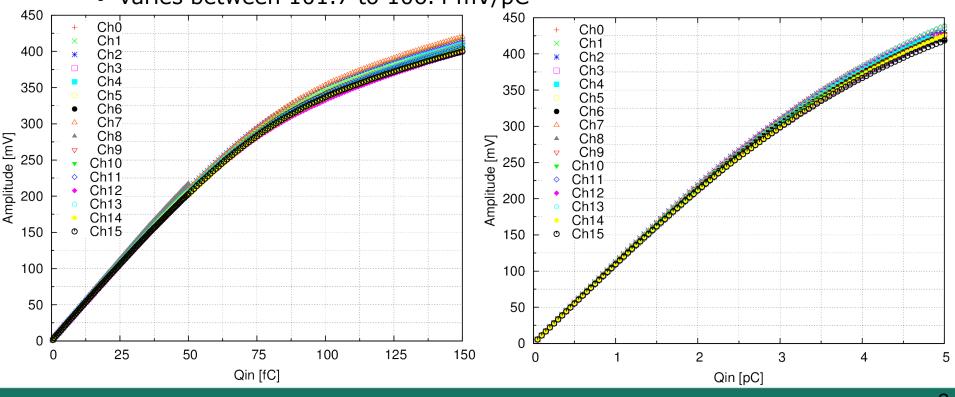
Measured shapes agree with simulations



# **Analog Front-End measurements Linearity**

- Measurements reasults with agreement with simulations
  - High gain 4.2 mV/fC (4.6 mV/fC from simulations) -
    - varies between 4.03 to 4.37 mV/fC
  - Low gain 105 mV/pC (113 mV/pC from simulations)

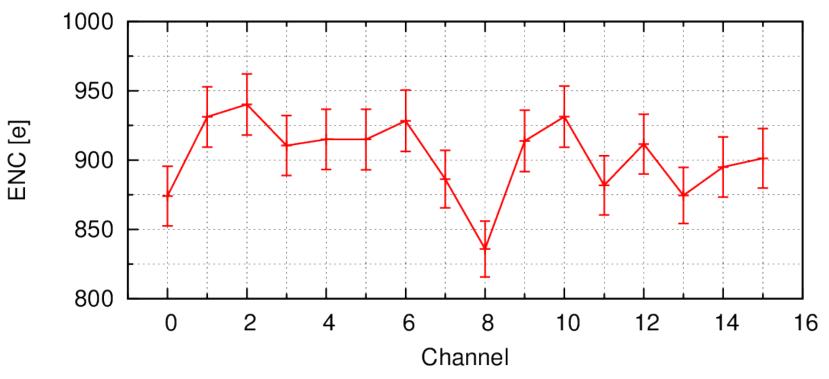






### **Analog Front-End measurements Noise performance**





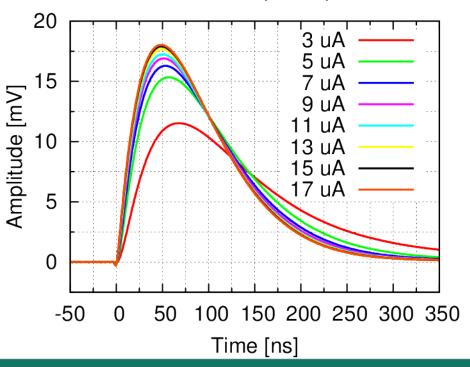
- Noise is uniform between the channels (two ASICs tested channels 0-7 from first ASIC and 8-15 from the second)
- ENC (Equivalent Noise Charge) is below 950 electrons giving SNR (Signal to Noise Ratio) in high gain mode above 25 for 1 MIP input charge

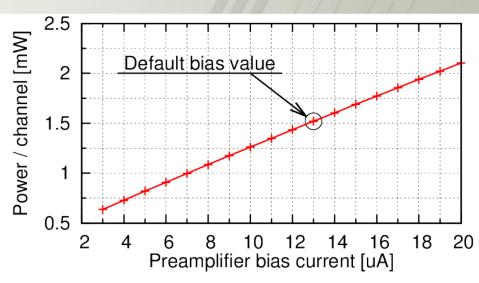


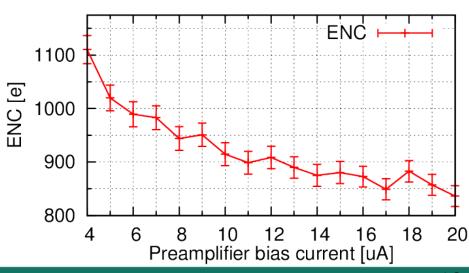
# Analog Front-End measurements Power consumption vs performance: Preamplifier bias current in high gain

- Power consumption at typical biasing
   1.5 mW / channel
- Power consumption may be decreased without significant decrease of performance

Pulses for various preamplifier bias









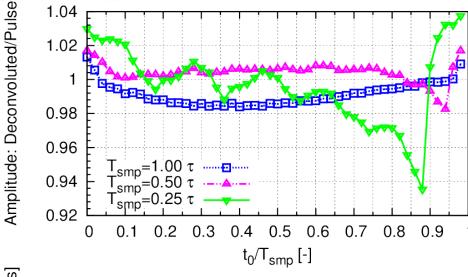
### **Analog Front-End measurements Summary**

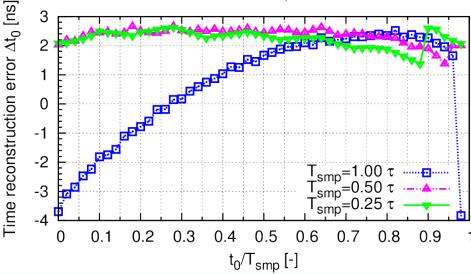
- Measurements results agree with simulations and specifications
  - Pulse shape and peaking time (50ns) as excepted
  - Gains in both modes differs within 10% from simulated
  - Baseline spread below 25 mV
  - Noise ENC at 10 pF below 1000 e-
  - Crosstalk measuremets:
    - High gain 0.64%
    - Low gain 0.80%
  - Power consumtion ~1.5 mW/channel can be reduced by lowering bias currents
  - All parameters uniform between channels (two ASICs measured)
- Detector capacitance measurements needs to be finished...



### Deconvolution for CR-RC shaping Real, averaged, FE pulses

- Real pulse (1 MIP) deconvoluted for various phase shift t0 between the Front-End pulse and ADC sampling
- Deconvolution done for different sampling periods (12.5, 25 and 50 ns are presented)
- Amplitude reconstruction (top plot) – deconvoluted to real pulse amplitude ratio
  - Error is below 2% except 12.5 ns sampling period
- Time reconstruction (bottom plot)
- difference between reconstructed and real pulse peak position
  - Constant offset of around 2 ns except 50 ns sampling period
- S/N after deconvolution still to be measured...

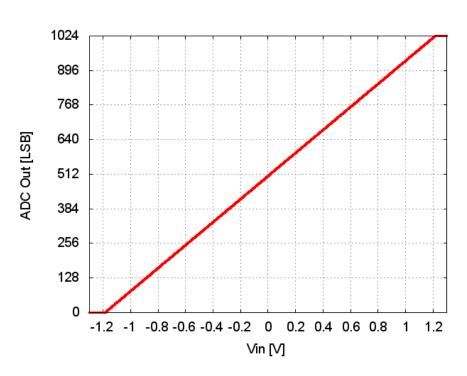




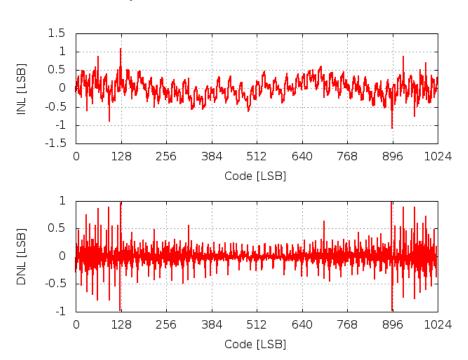


#### **10-bit SAR ADC in CMOS 130 nm Static measurement results**

#### Transfer function



#### INL/DNL measurements

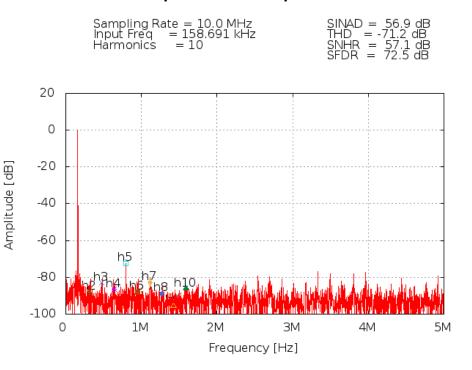


- ADC works well in the whole input signal range
- Generally, good linearity is measured, although for a few codes improvement is still needed

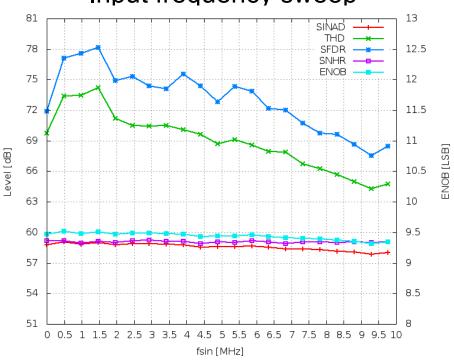


## 10-bit SAR ADC in CMOS 130 nm Dynamic measurement results (@20 MS/s)

#### **Example DFT Spectrum**



#### Input frequency sweep

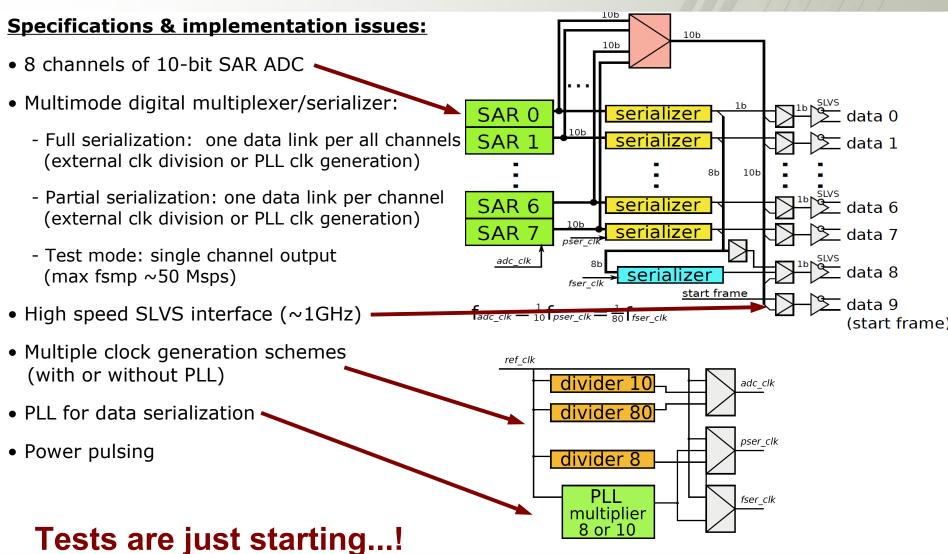


**ENOB~9.3** up to Nyquist input frequency for  $f_{sample} \sim 20 MHz \& P \sim 0.7 mW$ 

ADC works for  $f_{\text{sample}}$  beyond 40 MS/s, but above 20 MS/s ENOB start to decrease



### 8-channel 10-bit SAR ADC in CMOS 130 nm Architecture and Design





#### **Summary and Future Plans**

- New, low power, development of front-end electronics in CMOS 130 nm for LumiCal detector readout at linear collider is proceeding well
  - Low power 10-bit SAR ADC has been already positively verified and presented at TWEPP2013,
  - 2nd prototype of 8 channel ADC is fabricated and waiting for tests
  - 1st prototype of 8 channel analog front-end, shown here, is working well, some quantitive tests (e.g. Cdet dependence) still need to be done...
- We hope to integrate in NEW CMOS 130 nm and submit in 2015 (in one or two ASICs) the whole front-end containing preamp+shaper+ADC in each channel, and all other functionalities (DACs, I2C, PLL, DLL, SLVS) needed in complex SoC type chip

### Thank you for attention



#### **Testbeam preparation Status of four boards setup**

- Main problems: couplings between boards, noise and disturbances on power and gnd lines
- Old front-end in AMS 0.35um has bad PSRR
- A lot of work was done to optimize existing setup to allow multi-plane operation:
  - decoupling, shielding, improved regulators
- Presently the 4-plane setup after improvments behaves not much worse than single board before the changes
- We do not know what will happen after integration in the testbeam area...?